



PRESS RELEASE

Pollen & Wooptix Forge Strategic Partnership to Revolutionize Imaging with Smart3 Integration

The two companies will present live the integration strategy of their two technologies during the Exhibition SPIE Litho+Patterning taking place in San Jose on February 25-26

Moirans, February 20, 2025 – Pollen, a French leading software company specializing in Collaborative Al-powered process control software for Semiconductor Industry, and Wooptix, a Spanish leader in wavefront phase imaging applied to the semiconductor industry, have announced a strategic partnership to integrate Smart3 Software Platform technology into Wooptix's metrology equipment.

This collaboration combines **Pollen**'s expertise in process analysis and control with **Wooptix**'s cuttingedge imaging technology. By integrating **Smart3 Suite** into Wooptix's **Phemet**® metrology system, semiconductor manufacturers will benefit from enhanced wafer analysis and improved quality control processes.

A Major Breakthrough in Semiconductor Metrology & Inspection

Through this partnership, semiconductor manufacturers will gain access to a next-generation metrology solution that fuses:

- Wooptix's wavefront phase imaging technology for ultra-precise acquisition of silicon wafer topography data.
- Smart3's collaborative Al-powered process control software platform for intelligent data processing, fastest customization and improved industrial yield.

"This partnership represents a significant step forward for our customers, providing them with a next-generation Al-powered software solution SmartOEM3 directly integrated into Wooptix's equipment," said **Johann Foucher**, CEO of Pollen. "By combining our technologies, we will optimize quality control and increase the reliability of manufacturing processes."

For his part, **José Manuel Rodriguez Ramos**, CEO of Wooptix, added: "We are excited to collaborate with Pollen to enhance our metrology solutions. The integration of Smart3 into our Phemet® platform enables more powerful and automated metrology, essential to addressing the challenges of the semiconductor industry"

Live Demonstration at SPIE Lithography + Patterning [San Jose & 25-26 Feb. 2025]

Pollen and Wooptix will unveil their joint solution at the upcoming **SPIE Lithography + Patterning** event [San Jose & 25-26 Feb. 2025], showcasing a live demonstration of how the Smart3 integration enhances metrology capabilities.

About Pollen

Based in **Moirans, France**, **Pollen** is a software company specializing in optimizing manufacturing processes through advanced metrology, inspection and yield data analysis. Its flagship solution, **Smart3 Suite**, enhances product quality and optimizes industrial yield in semiconductor and high-performance materials industries.





About Wooptix

Founded in Spain, **Wooptix** is a pioneer in wavefront phase imaging for semiconductor metrology. Its **Phemet**® system enables precise characterization of silicon wafers, improving manufacturing process control and electronic component quality.

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